

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT

ATTY DOCKET NO.
230257US0SERIAL NO.
10/664,894APPLICANT
Nathalie JAGER-LEZERFILING DATE
September 22, 2003GROUP
1619

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/J.V./	AA	2002/098217	07/25/2002	B. Piot, et al.			
	AB	2003/0031642	02/13/2003	N. Jager Lezer			
	AC	2004/0142831	07/22/2004	N. Jager Lezer			
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	AF	3,802,841	04/09/1974	Jean-Baptiste Robin			
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	AC	6,491,931	12/10/2002	N. Collin			
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	DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO
AO	EP 1 201 221	05/02/2002	EPO (Corresponds to US 2002/098217)		X
AP	EP 1 053 742	11/22/2000	EPO (Corresponds to US 2006/057085) (English Abstract Provided)		X
AO	EP 1 208 836	05/29/2002	EPO	X	
AR	EP 0 445 342	09/11/1991	EPO	X	
AS	WO 00/72809	12/07/2000	WIPO	X	
AT	JP H09-263 518	10/07/1997	Japan (English Abstract Provided)		X
AU	JP 2002-154932	05/28/2002	Japan (English Abstract Provided)		X
AV	JP 2001-48736	02/20/2001	Japan (English Abstract Provided)		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

AW	
AX	
AY	
AZ	<input type="checkbox"/> Additional References sheet(s) attached

Examiner /Jyothsna Venkat/ Date Considered 05/25/2009

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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/J.V./	AO	JP 2001-48750	02/20/2001	Japan (English Abstract Provided)	X
	AP	JP 2002-145739	05/22/2002	Japan (Corresponds to US 2002/098217) (English Abstract Provided)	X
	AD	JP 2000-344627	12/12/2000	Japan (English Abstract Provided)	X
	AR	JP 2002-173412	06/21/2002	Japan (Corresponds to US 6,503,521)	X
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	AT				
	AU				
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